

Application/Control No.		Applicant(s)/Pa Reexamination	Applicant(s)/Patent under Reexamination	
10/64	0,346	WANG, JIAN	CHUNG	
Exam	iner	Art Unit		
Andre	e Pierre-Louis	2123		

SEARCHED					
Class	Subclass	Date	Examiner		
703	21,22	4/20/2006	APL		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (EAST (US- PGPUB;USPAT;USOCR;EPO;JPO;D ERWENT;IBM_TDB)- SEE ATTACHMENT	4/20/2006	APL
709/223 (Text Search Only_See search history printout)	4/20/2006	APL
714/4–43 (Text Search Only_See search history printout)	4/20/2006	APL